

<b>Notice of References Cited</b>	Application/Control No. 10/606,066	Applicant(s)/Patent Under Reexamination XU ET AL.	
	Examiner Jeff Natalini	Art Unit 2858	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,138,054	10-2000	On, Ching Tu	700/121
	B	US-6,011,404	01-2000	Ma et al.	324/765
	C	US-6,060,709	05-2000	Verkuil et al.	250/326
	D	US-5,963,783	10-1999	Lowell et al.	438/17
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yoshitake et al. "Measurement of work function change with surface segregation of substate element on a deposited film" May 1999. Applied Surface Science Volume 146, Issues 1-4, pgs 97-100.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.